

*XXIV. Erfahrungsaustausch
Oberflächentechnologie mit Plasma- und Ionenstrahlprozessen
Mühlleithen, 7. - 9. März, 2017*

Mikropartikel in einer optischen Pinzette: Messungen mit und ohne Plasma



Viktor Schneider und Holger Kersten

*Institut für Experimentelle und Angewandte Physik
Arbeitsgruppe Plasmatechnologie
Christian-Albrechts-Universität Kiel*

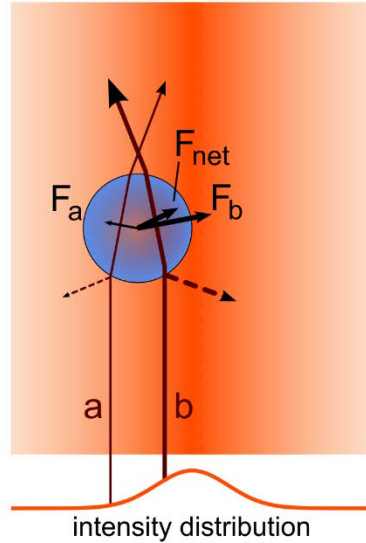
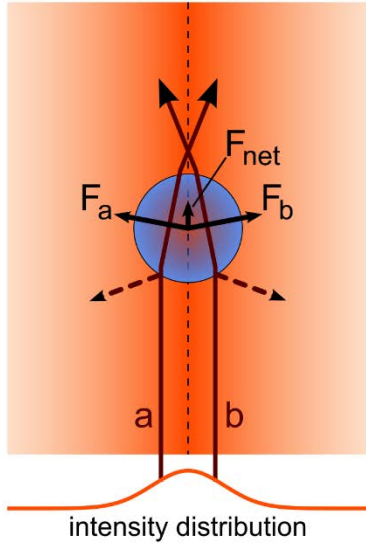
Outline



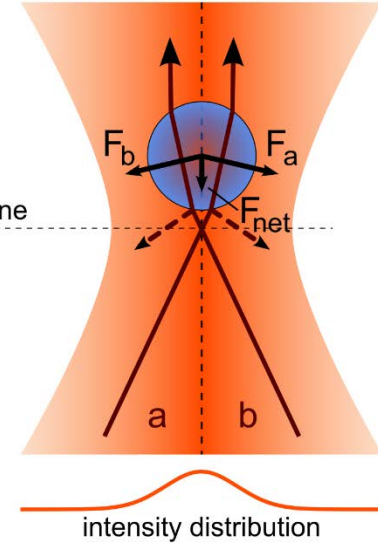
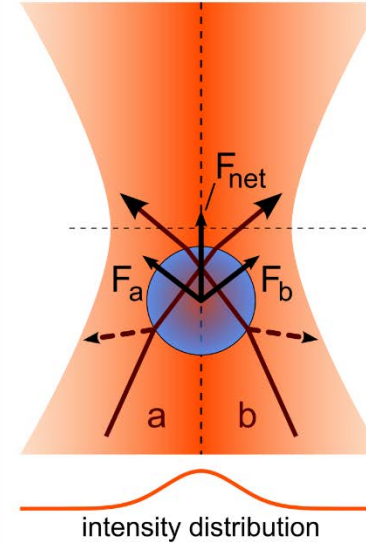
- I. Laser Trapping Principle
- II. Experimental Setup
- III. Position and Force Measurement
- IV. Measurements

Principle of Optical Tweezers

unfocused laser beam



focused laser beam



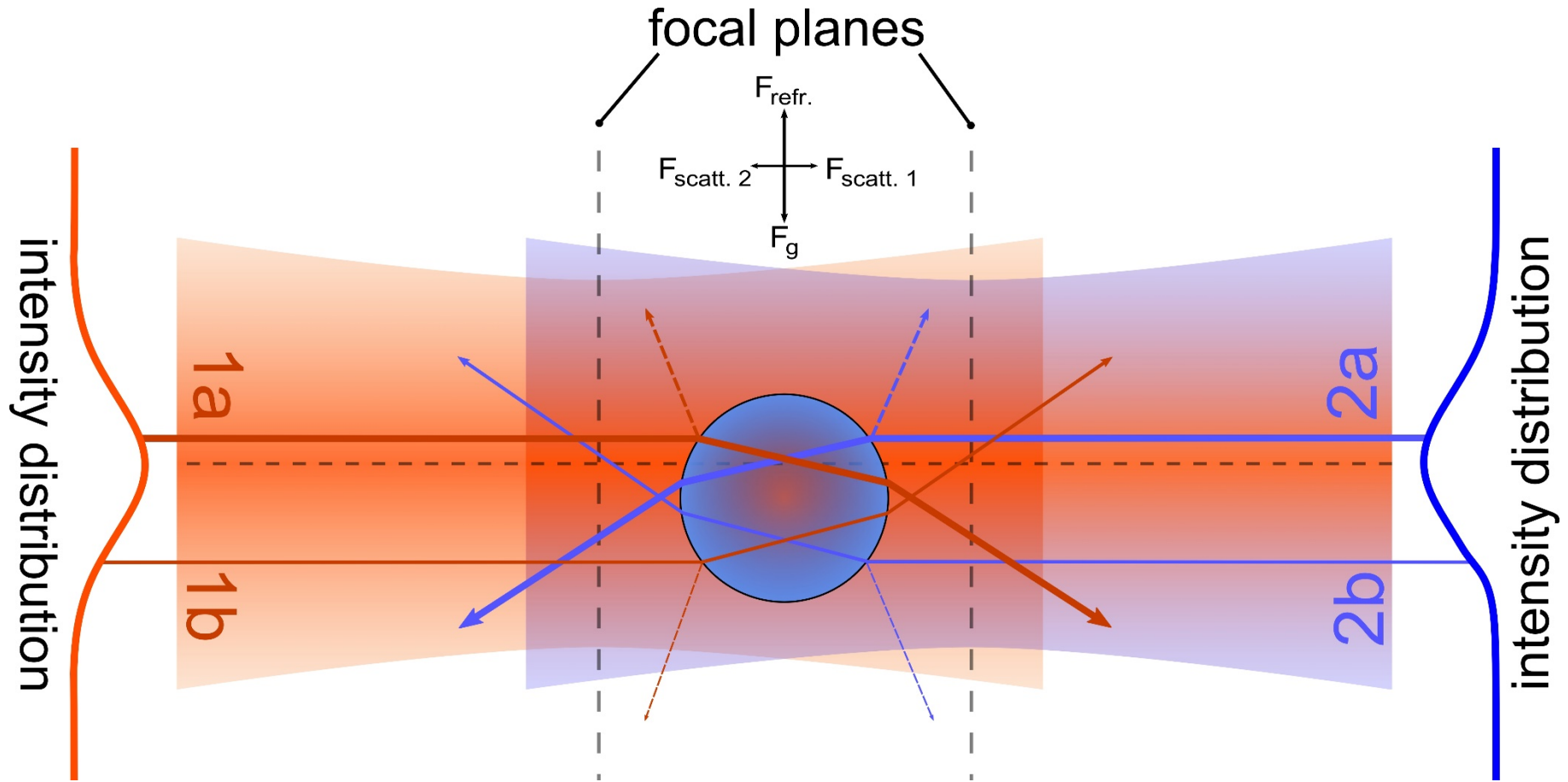
- ❖ gradient force: lateral component of F_{net}
- ❖ scattering force / radiation pressure: component along beam axis
- ❖ focused beam causes a force towards the focal point
- ❖ “single beam trap” (high NA necessary)

Review Article:

A. Ashkin, “History of Optical Trapping and Manipulation of Small-Neutral Particle, Atoms, and Molecules”, IEEE J. Sel. Top. Quant., **6**(2000)

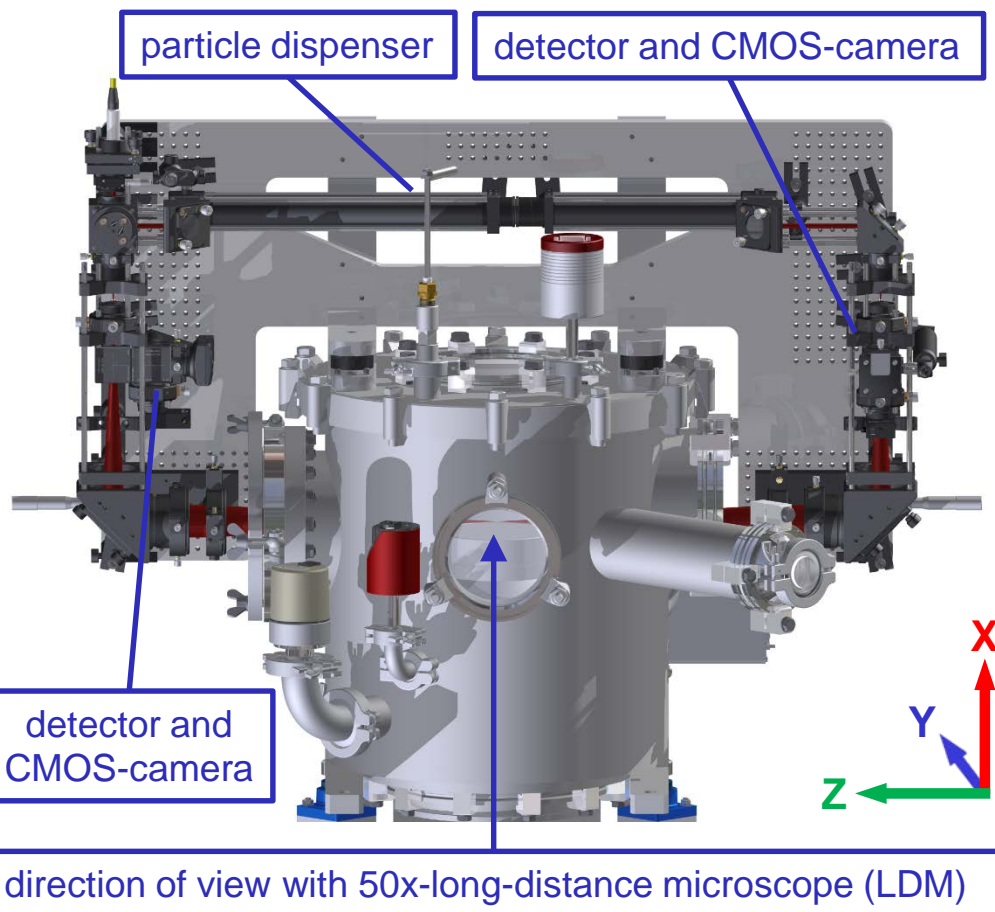
Principle of Optical Tweezers

dual counterpropagating beam trap

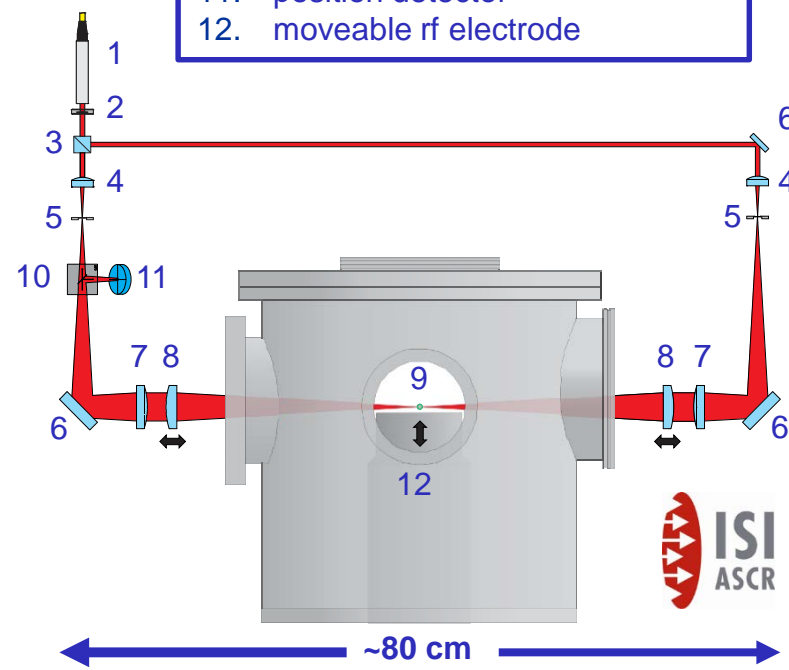


μPLASMA - microParticles in a Discharge with Laser Assisted Manipulation

- microparticle is optically trapped
- by moving the electrode up or down, the particle is moving relatively to the plasma



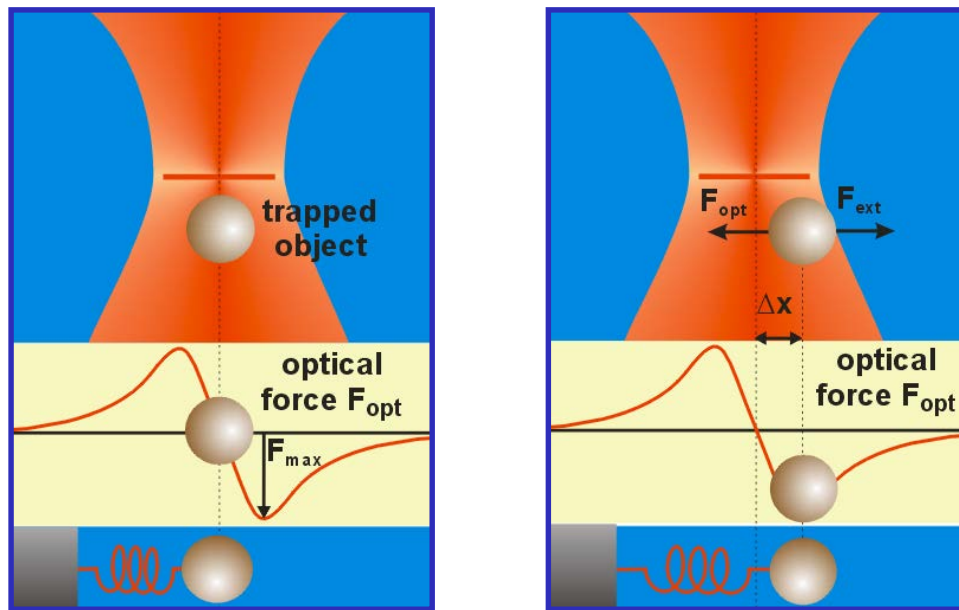
1. IR laser ($\lambda=1070\text{ nm}$)
2. $\lambda/2$ - plate
3. polarizing beamsplitter
4. beam expander
5. $10\ \mu\text{m}$ pinhole
6. mirror
7. collimator
8. focusing lens ($f = 30\text{ cm}$)
9. beam focus, particle
10. pellicle beamsplitter
11. position detector
12. moveable rf electrode



V. Schneider and H. Kersten, "On the use of optically trapped dust particles as micro-probes in process plasmas", Prob. At. Sci. Technol., 1(2013), 164

Position and Force Measurement

Force Measurement

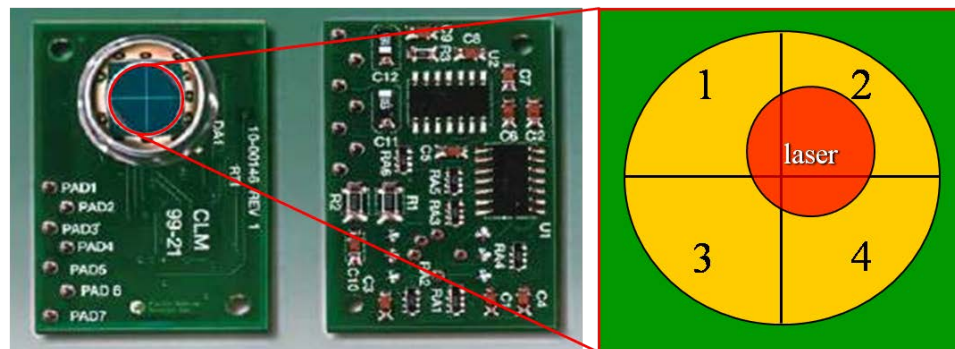


© Prof. Zemánek, Brno

- ❖ for small deviations Δx the force can be assumed as

$$F_{opt} = -\kappa \Delta x,$$

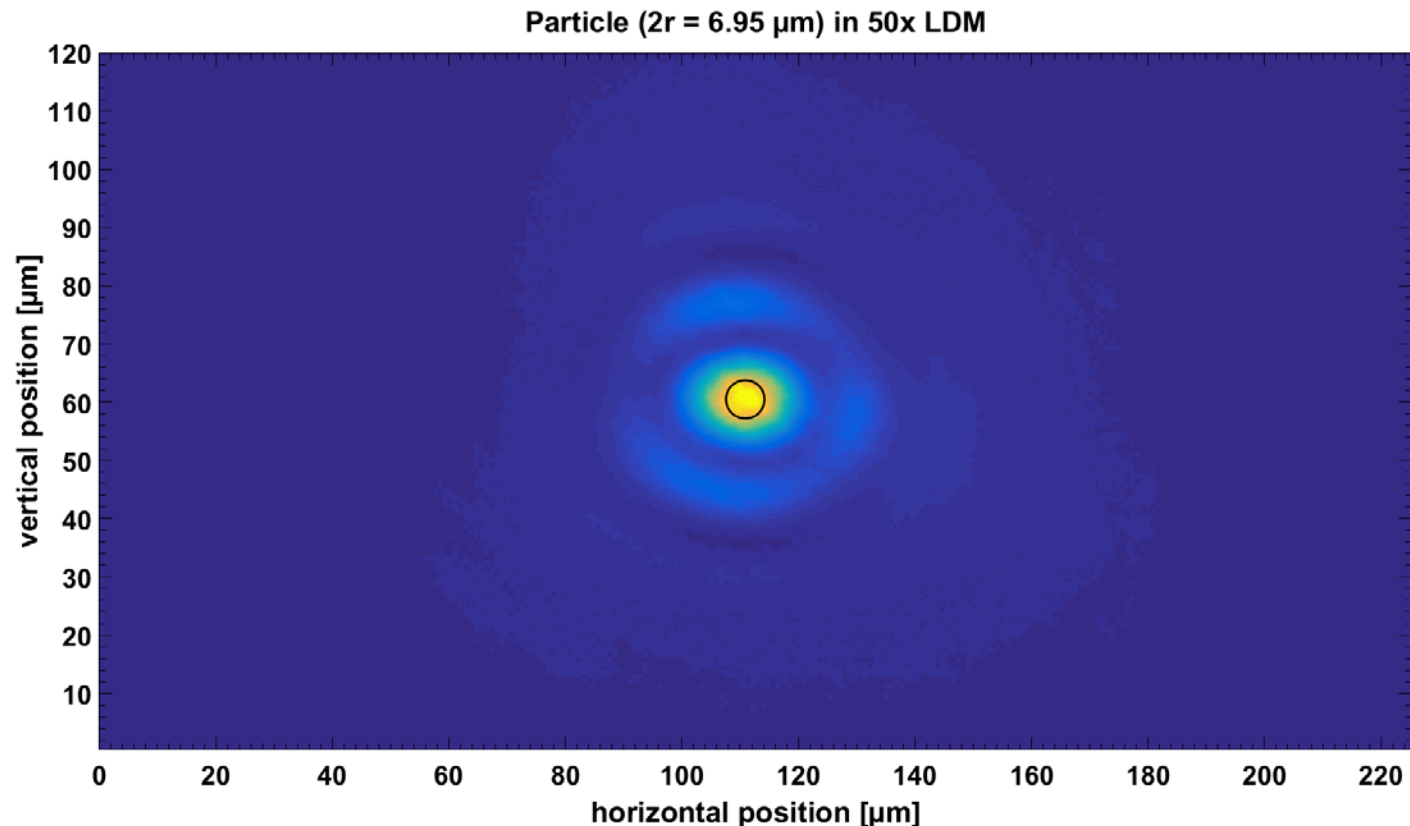
with the optical trap stiffness κ



- ❖ in a ray-optic approximation, the microparticle acts as a simple lens producing an intensity pattern, which depends on the object position
- ❖ a quadrant photodiode (QPD) is positioned in the optical axis

Position Measurement

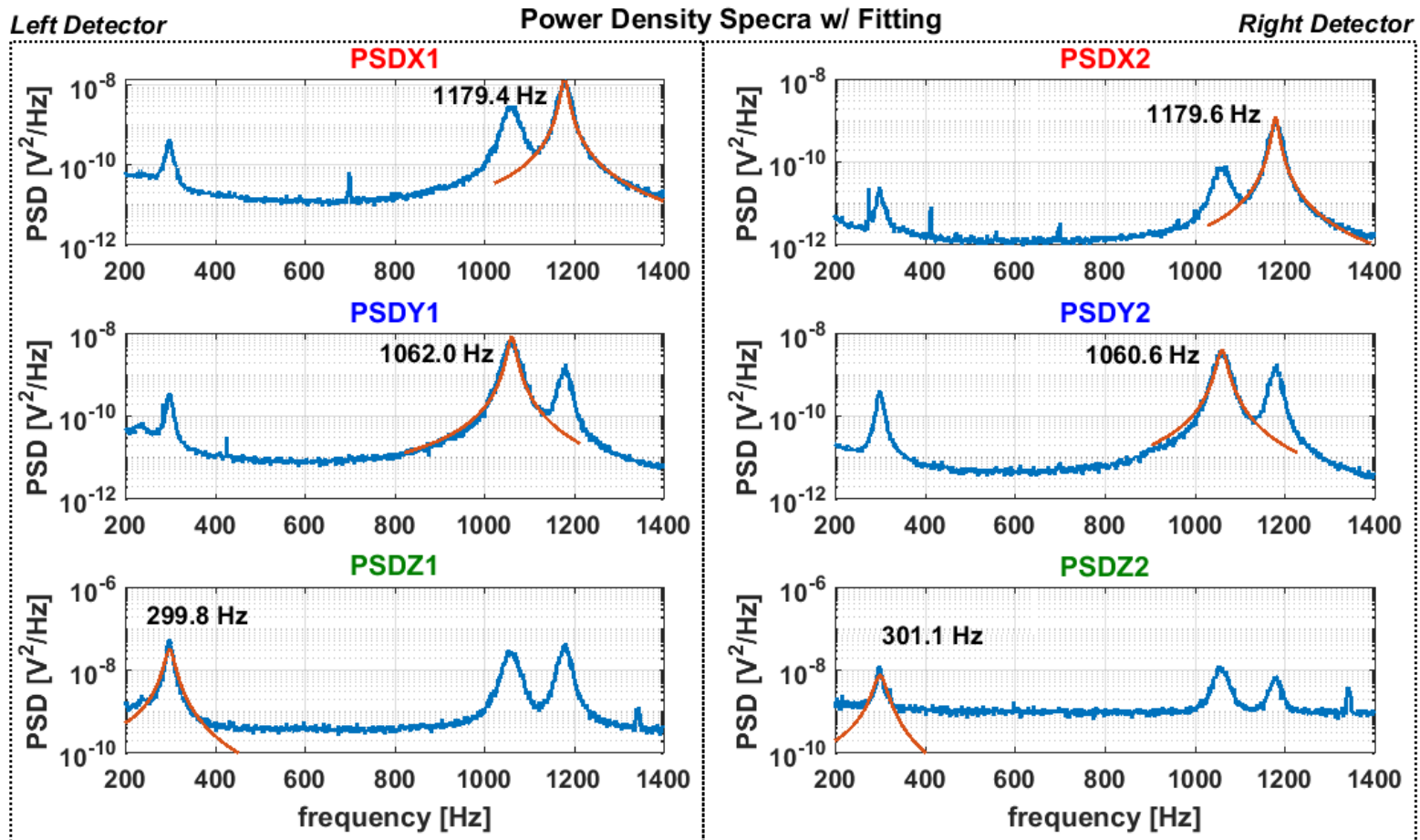
- ❖ particle observation with the 50x-Long-Distance-Microscope
- ❖ particle position with sub-pixel resolution is determined by intensity weighted centroid method ($1\text{px} \triangleq 0.11\mu\text{m}$)



B.C. Carter et. al., "Tracking single particles: a user-friendly quantitative evaluation", Phys. Biol. 2(2005), 60

Stiffness-Calibration Method

$$\ddot{x} + \gamma_0 \dot{x} + \omega_0^2 x = \frac{F_{therm}(t)}{m} \xi(t) \Rightarrow S(\omega) = \frac{2k_B T}{m} \frac{\gamma_0}{(\omega_0^2 - \omega^2)^2 + \omega^2 \gamma_0^2}, \quad \omega_0 = \sqrt{\kappa/m}$$

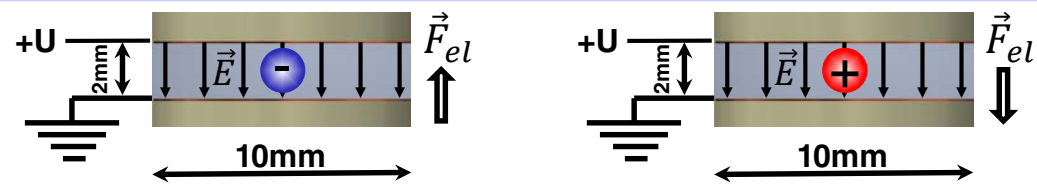
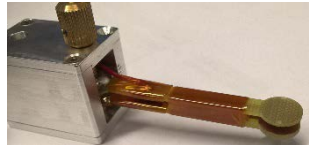


T. Li and M. G. Raizen, "Brownian motion at short time scales", *Ann. Phys. (Berlin)* **525**(2013), 281–295

J. Gieseler et al., "Subkelvin Parametric Feedback Cooling of a Laser-Trapped Nanoparticle", *Phys. Rev. Lett.* **109**(2012), 103603

Measurements

UV Light Charging / Decharging



μ Particle negative

μ Particle positive

μ Particle negative

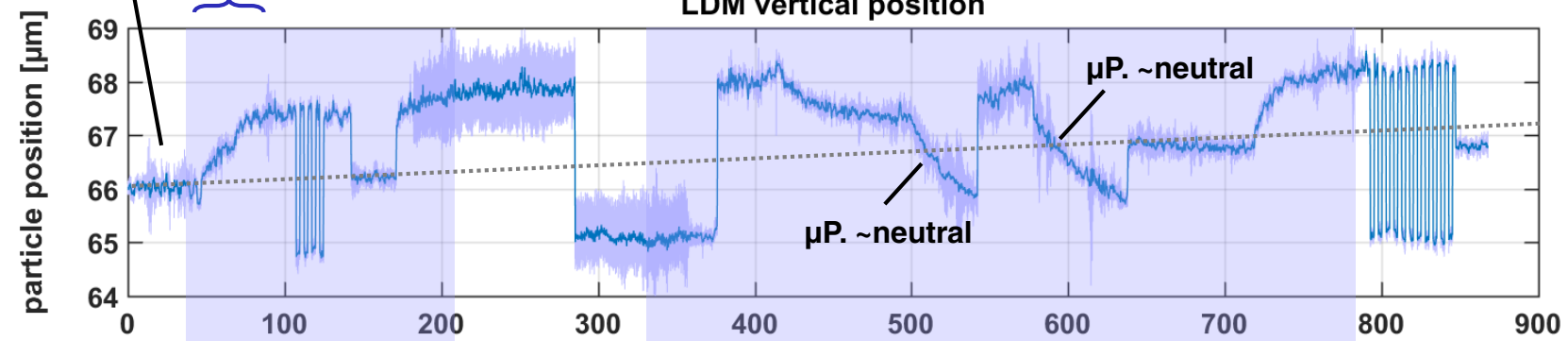
μ P. ~neutral

negative charging

positive charging

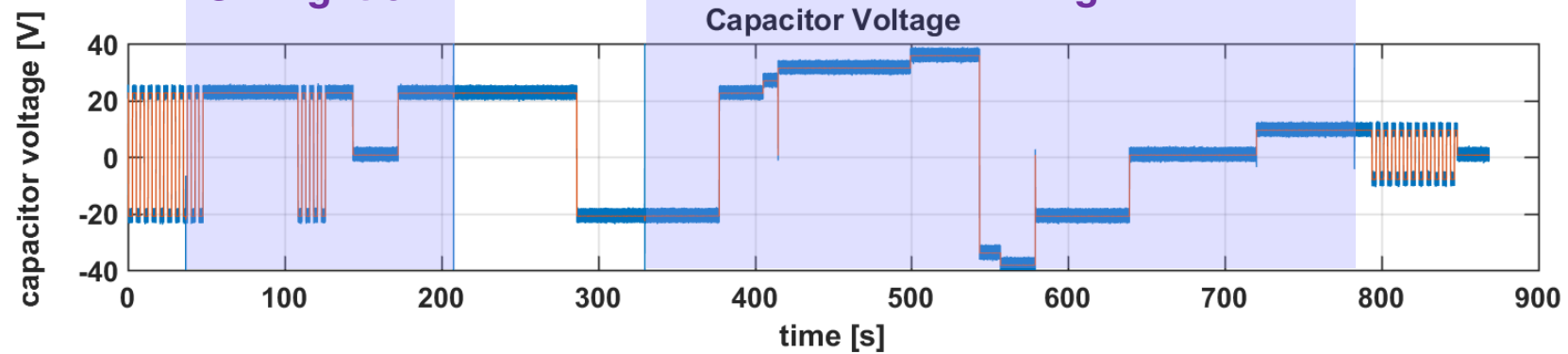
negative charging

LDM vertical position



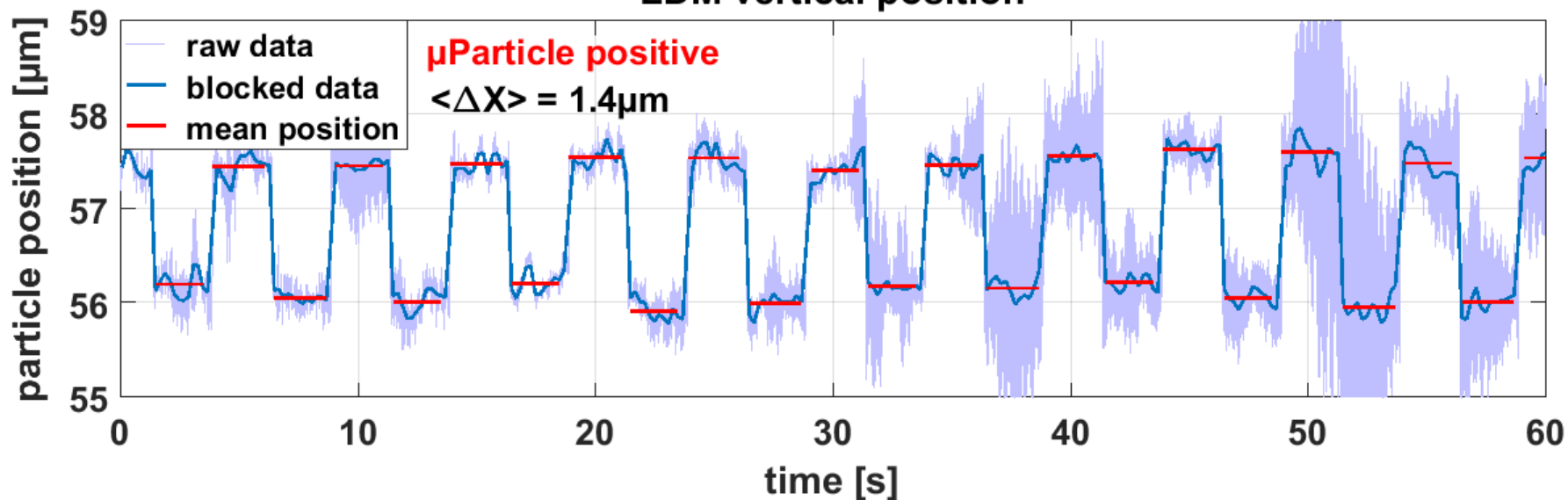
UV Light on

UV Light on

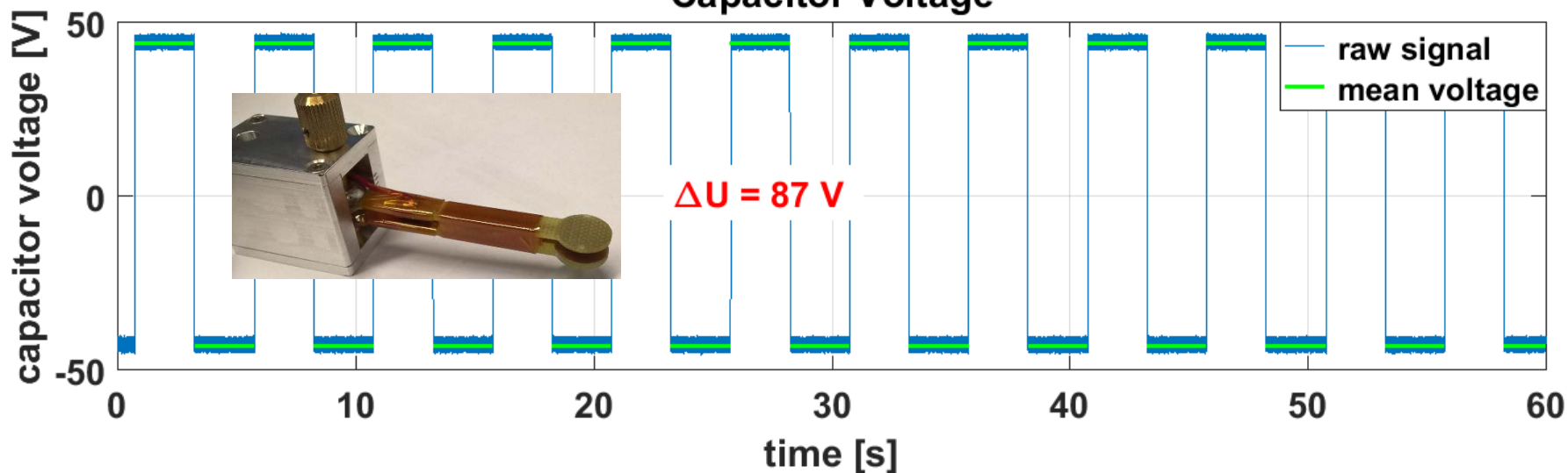


UV Light Charge Estimation

LDM vertical position



Capacitor Voltage



UV Light Charge Estimation

with $\omega_0 = 2\pi \cdot 1179 \text{ Hz}$ and $\kappa = \omega_0^2 \cdot m = 17.8 \text{ pN}/\mu\text{m}$

with $\Delta x \approx 1.4 \mu\text{m}$

$$\Rightarrow F_{el} \approx 24.9 \text{ pN}$$

with $U = 86.98 \text{ V}$ and $d = 0.002 \text{ m}$

$$\Rightarrow E = U/d = 43492 \text{ V/m}$$

$$\Rightarrow Q = F_{el}/E = 5.91 \text{ e}^{-16} \text{ C} \approx +3680 \text{ e}$$

charging with a filament leads to a charge of

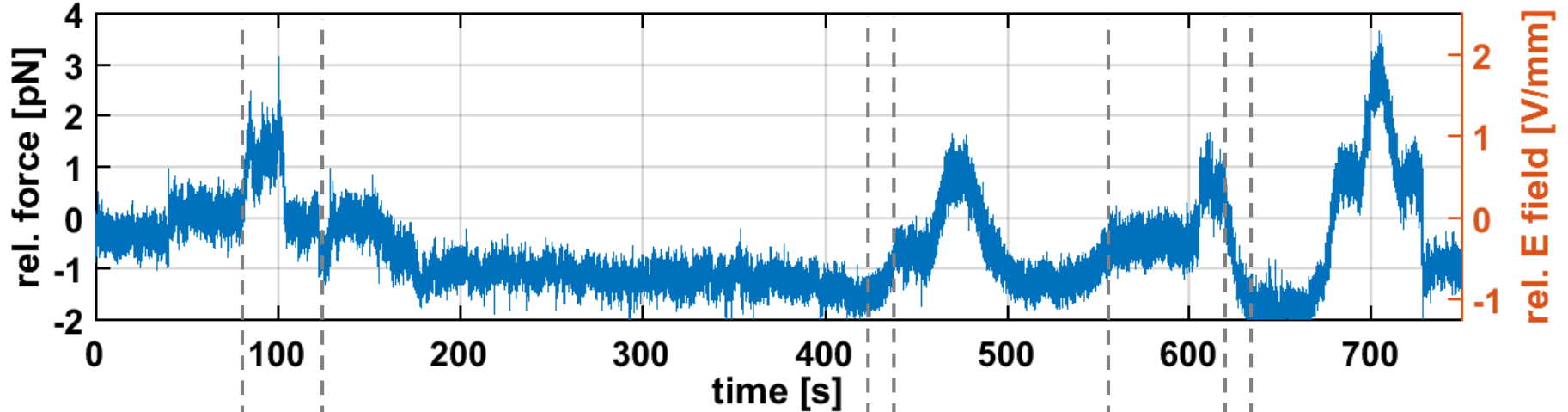
$$Q \approx -14000 \text{ e} \dots -18000 \text{ e}$$

residual charges after the plasma are always positive

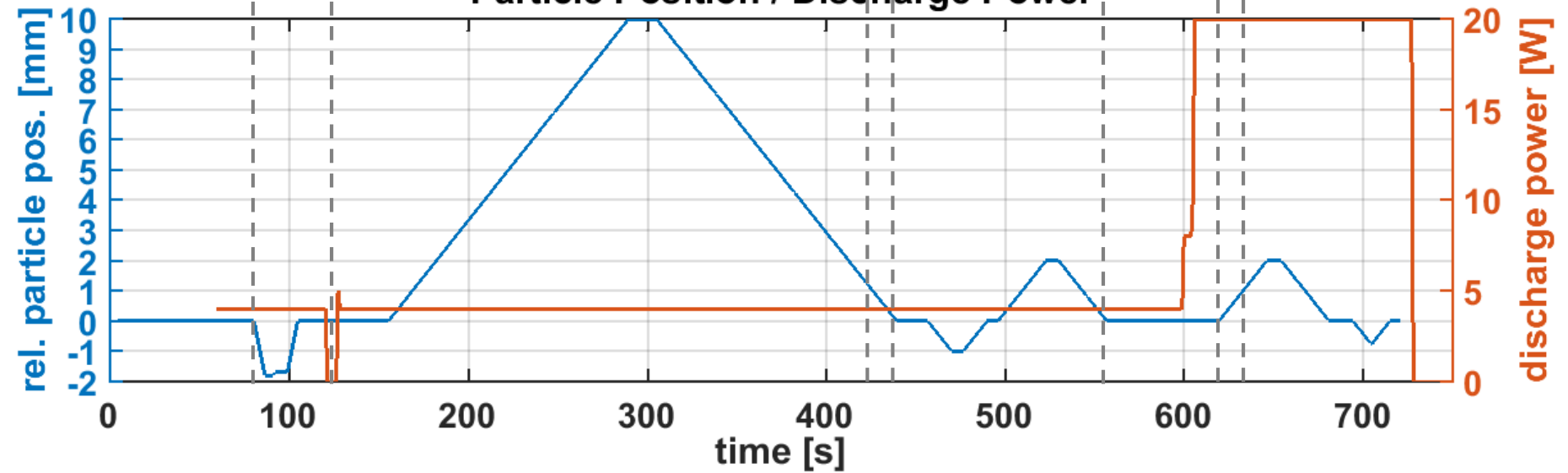
$$Q_{res} \approx +500 \text{ e} \dots +1000 \text{ e}$$

Plasma Sheath

Measured Relative Forces / Electric Fields



Particle Position / Discharge Power



Thank you!
